

Search Notes

Application/Control No.

10/600,014

Examiner

Shew-Fen Lin

Applicant(s)/Patent under
Reexamination

CHATTERJEE ET AL.

Art Unit

2166

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Google	3/21/2007	SFL
East (US-PUB, USPAT, USOCR, EPO, JPO, IBM-TDB	3/21/2007	SFL